



Processing and Cleaning Techniques for Modern Accelerator Vacuum Systems

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Aims

- To understand why we need to adopt a rigorous cleaning and processing strategy for vacuum especially modern accelerators
- To understand some of the techniques involved
- To understand some of the aspects of quality control for vacuum

Why Do We Need To Clean For Vacuum?

- We may not need to!
- It depends on what we need vacuum for:
 - Vacuum regime required
 - Ultimate pressure
 - Cleanliness
 - So we need to make a proper assessment of the real requirements of the application
- But in general, modern accelerators require good, “clean” vacuum

Some Reasons for Cleaning

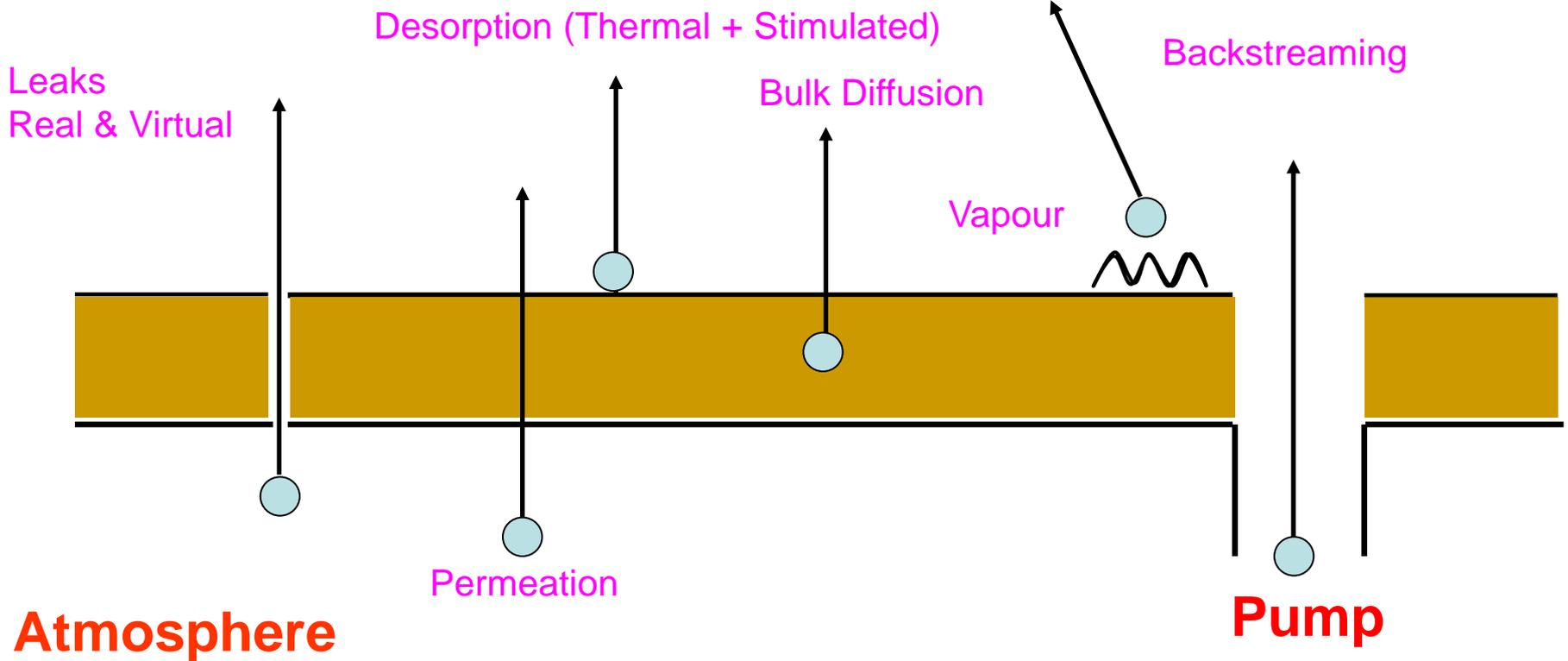
- Irrespective of application - manufacturer desires attractive appearance!
- Characteristics of a surface (surface properties) may be altered by ‘contamination’ at the surface.
- Processes may be poisoned by ‘contaminants’

What strategy should be adopted?

- The least that is proved to be effective for the task in hand
- But understand what is required and the limitations of each process
- Design for cleaning
- Pay enormous attention to detail
- Pay enormous attention to health and safety!

Sources of Residual Gas

Vacuum



Atmosphere

Pump

- So to Reduce Residual Gas, we must Inhibit or Reduce these processes

Outgassing Rates of Materials in Vacuum

- The outgassing rates may vary in order of magnitudes depending on factors: choice of material, **cleaning procedure**, history of material, pumping time, etc...
- Not all materials are compatible with UHV and XHV system!

Material	η_t (mbar ·lt/s/cm ²)
Aluminium (fresh)	$9 \cdot 10^{-9}$
Aluminium (20h at 150°C)	$5 \cdot 10^{-13}$
Copper (24h at 150°C)	$6 \cdot 10^{-12}$
Stainless steel (304)	$2 \cdot 10^{-8}$
Stainless steel (304, electropolished)	$6 \cdot 10^{-9}$
Stainless steel (304, mechanically polished)	$2 \cdot 10^{-9}$
Stainless steel (304, electropolished, 30h at 250°C)	$4 \cdot 10^{-12}$
Stainless steel (316, vacuum fired, 950°C 2-4 hours)	$5 \cdot 10^{-14}$
Perbunan	$5 \cdot 10^{-6}$
Pyrex	$1 \cdot 10^{-8}$
Teflon	$8 \cdot 10^{-8}$
Viton A (fresh)	$2 \cdot 10^{-6}$



Pumping speed

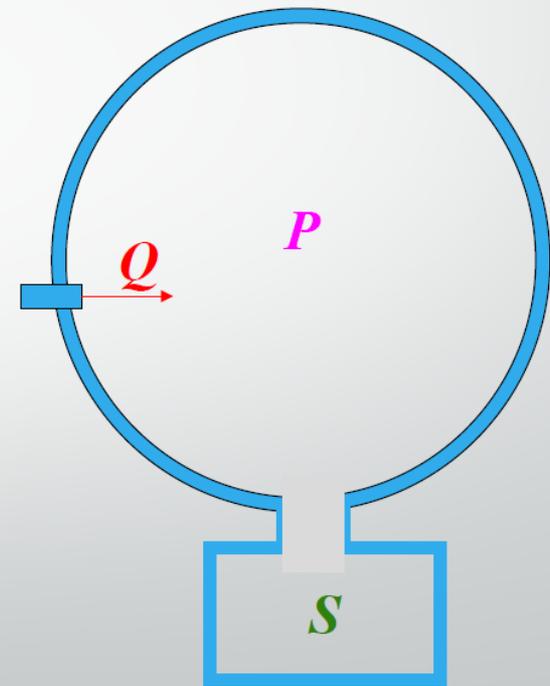
Pressure P [mbar] in a vacuum vessel is defined by the total gas load, Q [mbar·l/s], and total pumping speed, S [l/s].

In the case of very simple vacuum chamber it is :

$$P = \frac{Q}{S} \quad \text{Vacuum Plumbers' Formula 1}$$

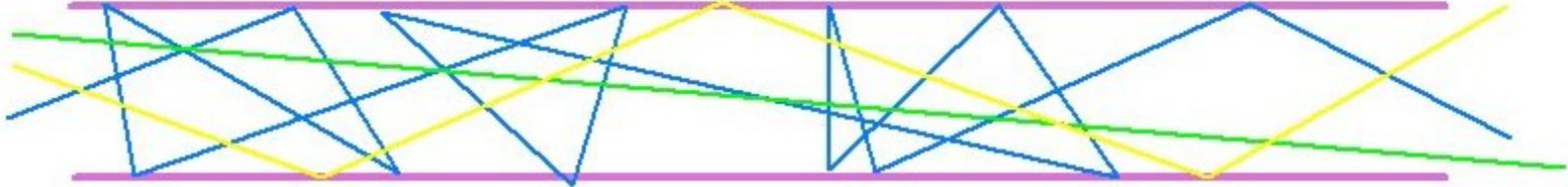
For $Q = 10^{-6}$ mbar·l/s and $S = 100$ l/s the pressure in vacuum chamber:

$$P = 10^{-8} \text{ mbar}$$





Conductance Limitations



α is dependent only on the ratio of length to diameter dimension, and the shape of the cross section of the duct.

For a cylindrical pipe:

L/D	α
0	1
0.5	0.67
1	0.51
10	0.11
50	0.025

It is common in accelerators for the L/D ratio to be large, hence the restriction in transmission probability.

$$C = \alpha C_A$$

Simplest Equation in Vacuum Science:

$$P = Q/S$$

Q = Outgassing Rate

P = Pressure

S = Pumping Speed



Outgassing rate v Pumping Speed

- In general, *in particle accelerators*, the effective S varies between 1 to 1000 l.s⁻¹) while Q **can extend over more than 10 orders of magnitude** ($\approx 10^{-5} \rightarrow 10^{-15}$ mbar l.s⁻¹.cm⁻²).
- The **right choice of materials and treatments** is compulsory in the design of vacuum systems (especially those for accelerators).
- In this respect the **measurement of outgassing rate is an essential activity** for an ultra-high vacuum expert.

Cleaning for Accelerators – Why?

- **It's all about the end product, what do we want to achieve....**
 - **Particles to pass through accelerator WITHOUT scattering**
 - Maintain Satisfactory Lifetime Stored Electron Beam
- **Electron Scatter \propto Atomic Number²**
- **Reduce Outgassing Rates - Low Presence of High Mass Species**
 - Hydrocarbons < 0.1% Pump Lubricants < 0.01%
- **Stimulated desorption – Usually the MAJOR Gas Load**
 - Photon Stimulated **Desorption** (PSD)
 - Electron Stimulated **Desorption** (ESD)
 - Ion Impact **Desorption**
 - Increased Thermal **Desorption**
- **Maintain Clean In-Vacuum Surfaces**
 - Coating Deposition
 - Prevent Particle Target Poisoning
 - Maintain Efficient Optical Properties for EM Radiation Transport

 **Cleanliness is an 'Essential Step' in achieving this**



Requirements for UHV/XHV

- Minimise desorption
 - Remove ‘contaminants’ (i.e. components with high outgassing/vapour pressure)
 - Deplete reservoirs
 - Bulk gases
 - Surface overlayers (e.g. adventitious graphite)
 - Provide barriers – passivation techniques



Vacuum

- Much ado about nothing!
 - Nature abhors a vacuum
 - We have to work quite hard to get low pressures
 - Understand limitations
- There's nothing in it!

Outgassing

Pumping

	Particles m ⁻³
Atmosphere	2.5×10^{25}
Vacuum Cleaner	2×10^{25}
Freeze dryer	10^{22}
Light bulb	10^{20}
Thermos flask	10^{19}
TV Tube	10^{14}
Low earth orbit (300km)	10^{14}
SRS/Diamond	10^{13}
ALICE	10^{11}
Surface of Moon	10^{11}
Interstellar space	10^5

Define your requirements

- F
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- i
- S



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Vacuum Systems

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Vacuum Systems

ASTEC-VAC-QCD-ipc-005

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Acceptance Tests for Vacuum Vessels, Components and Assemblies for ASTeC

JHV

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R J Reid

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Ultra High Vacuum Guide

CLRC Daresbury Laboratory
 Synchrotron Radiation Department
 Vacuum Support Group.

A compendium of Procedures and Specifications
 <Issue 3>

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Accelerators + Vacuum

- Particle accelerators come in many shapes and sizes and require different vacuum pressures:
 - Small LINACs - 10^{-5} – 10^{-6} mbar
 - Medical Cyclotrons
 - Electrostatic
 - Synchrotrons - 10^{-7} – 10^{-8} mbar
 - Leptons
 - Hadrons
 - Storage Rings- 10^{-9} – 10^{-10} mbar
 - Synchrotron Light Sources
 - Colliders + ERL's - 10^{-11} – 10^{-12} mbar
 - LHC
 - ILC

Quality Control

- Accelerator builders are, in general, always building high precision prototypes which must work to a stringent specification.
- To achieve this, good quality control or quality assurance is essential.
- QA systems such as those set up under standards like ISO 9001 are well established and the mechanical aspects of vessel and component manufacture (e.g. materials, dimensions, tolerances) will fall under their aegis.



Quality Control

- Vacuum aspects of quality control are much more nebulous
- The system builder needs to specify exactly what is wanted, how it is to be measured and how it is to be assessed.
- There are no “standard” standards.
- It is also likely that contractors will need to be educated and vacuum equipment may need to be supplied.
- Trained vacuum inspectors will also need to be available.

Quality Control

- First define your standards.



Quality Control

- General vacuum specification
 - Materials
 - Techniques
 - Processes
 - Handling
 - Inspection
- (In addition to vessel drawings, mechanical specification, etc.)

Accelerators + Vacuum

•Standard Cleaning Procedure for Stainless Steel Components

Preclean

1.Remove all debris such as swarf by physical means such as blowing out with a high pressure air line, observing normal safety precautions. Remove gross contamination by washing out, swabbing or rinsing with any general purpose solvent. Scrubbing, wire brushing, grinding, filing or other mechanically abrasive methods may not be used (see 5.2 above).

Wash

- 1.Wash in a high pressure hot water (approx. 80°C) jet, using a simple mild alkaline detergent. Switch off detergent and continue to rinse thoroughly with water until all visible traces of detergent have been eliminated.
- 2.If necessary, remove any scaling or deposited surface films by stripping with alumina or glass beads in a water jet in a slurry blaster.
- 3.Wash down with a high pressure hot (approx. 80°C) water jet, with no detergent, ensuring that any residual beads are washed away. Pay particular attention to any trapped areas or crevices.
- 4.Dry using an air blower with clean dry air, hot if possible.

Chemical Clean

- 1.Immerse completely in an ultrasonically agitated bath of clean hot stabilised trichloroethylene for at least 15 minutes, or until the item has reached the temperature of the bath, whichever is longer.
- 2.Vapour wash in trichloroethylene vapour for at least 15 min minutes, or until the item has reached the temperature of the hot vapour, whichever is longer.
- 3.Ensure that all solvent residues have been drained off, paying particular attention to any trapped areas, blind holes etc.
- 4.Wash down with a high pressure hot (approx. 80°C) water jet, using clean demineralised water. Detergent must not be used at this stage.
- 5.Immerse in a bath of hot (60°C) alkaline degreaser (P3 Almeco™ P36 or T5161) with ultrasonic agitation for 5 min. After removal from the bath carry out the next step of the procedure immediately.
- 6.Wash down with a high pressure hot (approx. 80°C) water jet, using clean demineralised water. Detergent must not be used at this stage. Ensure that any particulate deposits from the alkaline bath are washed away.
- 7.Dry in an air oven at approx 100°C or with an air blower using clean, dry, hot air.

Finishing

- 1.Allow to cool in a dry, dust free area. Inspect the item for signs of contamination, faulty cleaning or damage.
- 2.Pack and protect as in 5.6.3 above.

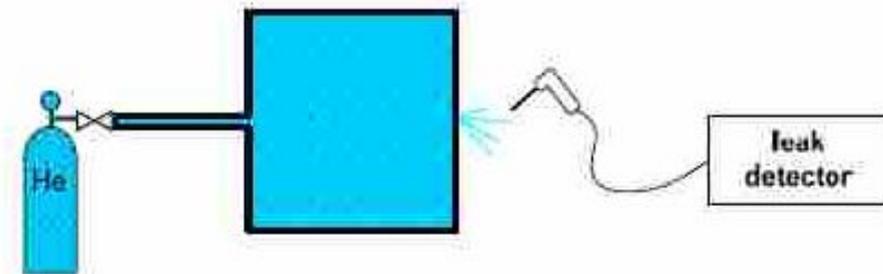
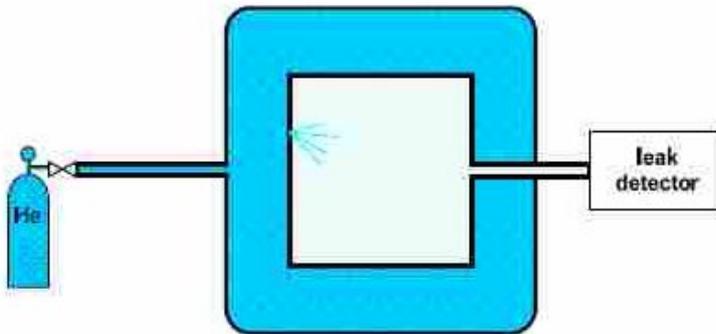
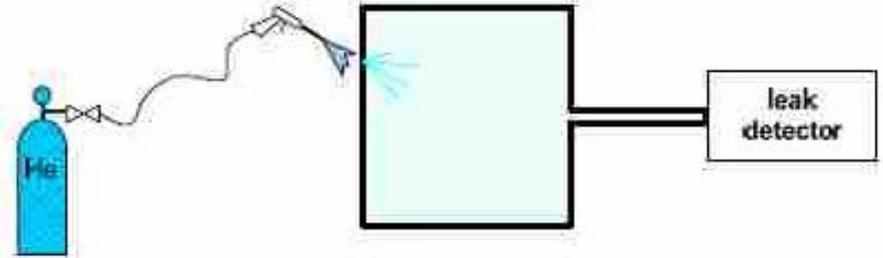


Quality Control

- Assessment (Tests)
 - Leak test
 - Performance test
 - Base pressure
 - Outgassing rate
 - Cleanliness

Leak tests

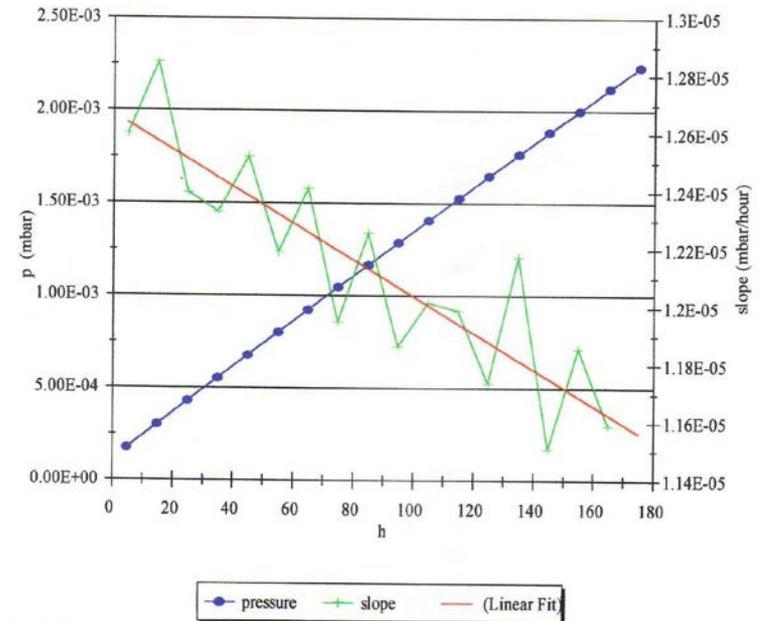
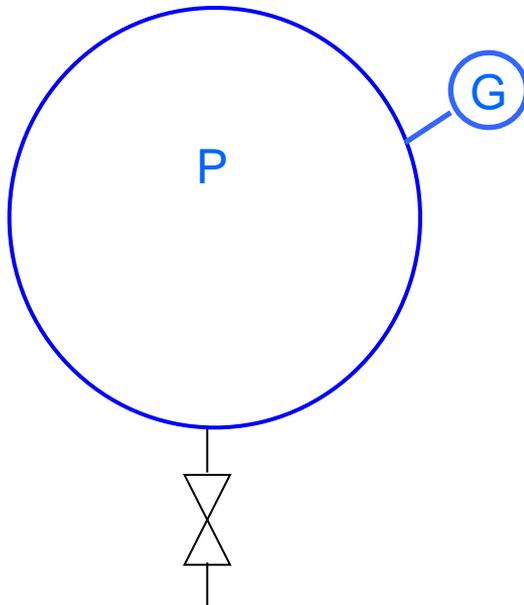
- Specify a realistic leak rate
- Specify testing method



Outgassing test

- Rate of Rise (gas accumulation)

In a sealed chamber, $Q = \frac{dP}{dt}_{t=0} \cdot \frac{V}{A}$





**How are we going to
achieve it?**

Broad Range of Methods Available

Chemical	Thermal Treatment	Polishing	In-Situ Treatment	Others...
Wash – Detergent or Solvent	Vacuum Bakeout	Electro- Polish	Vacuum Bakeout	Bead Blasting
Ultrasonic – Aqueous or Solvent	Vacuum Fire (typical ~950C for STST)	Diamond Paste Machine/Manual	UV Lamps	CO2 Snow
Vapour Clean– Solvent	Air Bake (up to ~ 400C)	Plasma Etch	Glow Discharge	
ACID Etch – Pickling or Passivation	Vacuum Remelt	Diamond Turning	Chemical	
Power Wash – Water Jet		BCP-Buffered Chemical Polishing		



- Wear gloves!



Work on clean aluminum foil.

Cover any chamber openings with foil and clean plastic covers.



- Use clean tools.



Finger prints outgas at the rate of 1×10^{-5} mbar Liters per second! Leaving finger prints on UHV components may prevent the chamber from pumping to a low enough pressure. The same goes for anything else that may leave oil on a UHV component.



Chemical

Chemical
Wash – Detergent or Solvent
Ultrasonic – Aqueous or Solvent
Vapour Clean– Solvent

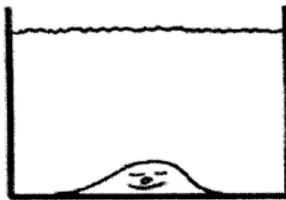
Typical Cleaning Agents

Agent	Examples	Advantages	Disadvantages	Disposal
Water		Cheap, readily available	Need de-min for cleanliness. Not a strong solvent	To foul drain
Alcohols	Ethanol, methanol, iso-propanol	Relatively cheap and readily available. Quite good solvents	Need control – affect workers; some poisonous; some flammable; stringent safety precautions.	Evaporate or controlled disposal.
Organic Solvents	Acetone, ether, benzene	Good solvents, evaporate easily with low residue.	Either highly flammable or carcinogenic	Usually evaporate
CFC's	Freon™ (CFC-113)	Excellent solvents; evaporate easily with low residue	Banned	Strictly controlled, must not be allowed to evaporate
Chlorinated hydrocarbons	Trichloroethylene (Trike™)	Excellent solvents. Non-toxic. Low boiling point. Low residue	Toxic, requires stringent safety precautions.	Strictly controlled
Detergents		Aqueous solutions, non toxic. Cheap and readily available. Moderate solvents.	Require careful washing and drying of components. Can leave residues.	To foul drain and dilution
Alkaline degreasers	Almecco™ sodium hydroxide	Aqueous solutions, non- toxic. Moderate solvents	Can leave residues and may throw particulate precipitates	Requires neutralisation, then dilution to foul drain.

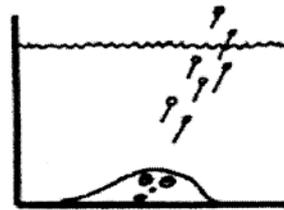


Science of Cleaning

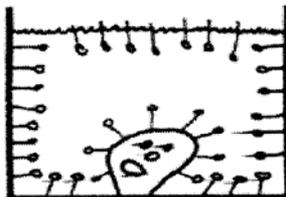
- **Solvent** - A **solvent** is a substance that dissolves another substance or substances to form a *solution* (a homogeneous *mixture*). The solvent is the component in the solution that is present in the largest amount or is the one that determines the *state of matter* (i.e. solid, liquid, gas) of the solution.



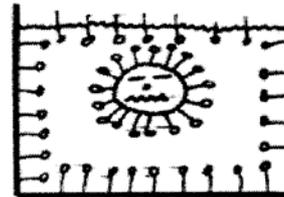
Oily soil.



Detergent attack on soil.



Orientation of hydrophilic and hydrophobic ends



Soil is surrounded, lifted, suspended, and dispersed

Hydrophile

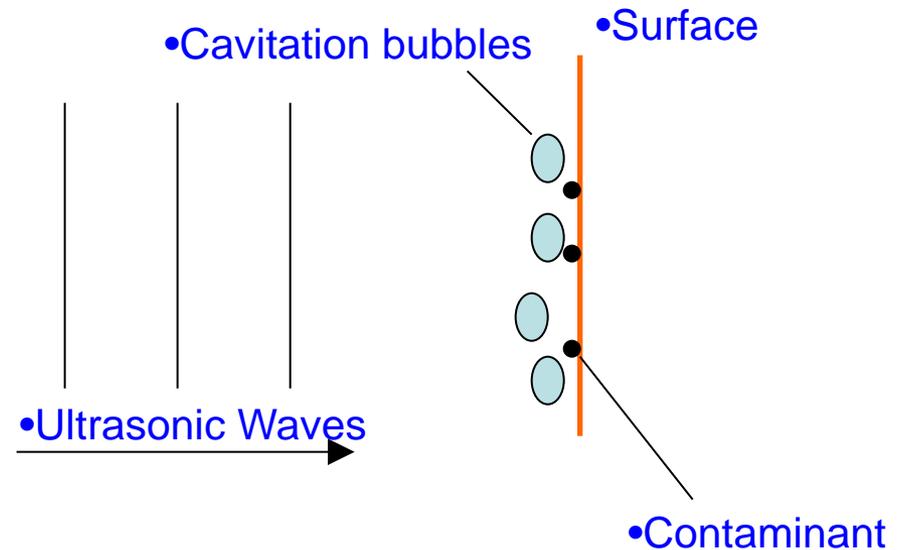
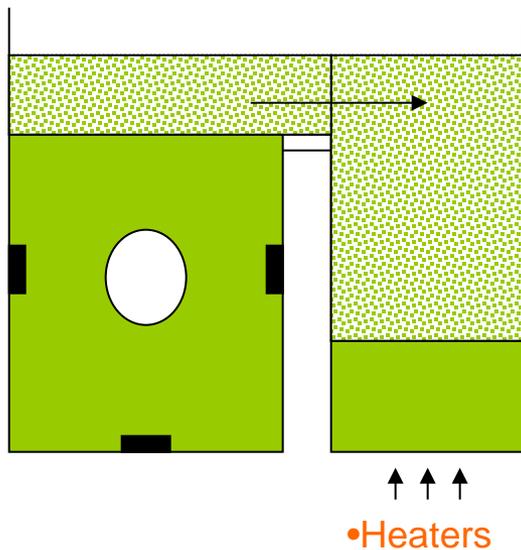


Hydrophobe

Aqueous & Solvent Cleaning

- **Special Cleaning Techniques**

Ultrasonic cleaning - widely used



Cleaning Process

- Full detailed procedure in ASTeC spc-003 - Cleaning of vacuum items



- Power wash booth for large items



- Auto washers for small items



Solvent wash, HFE72DE



• 2 x Solvent cleaning plants:

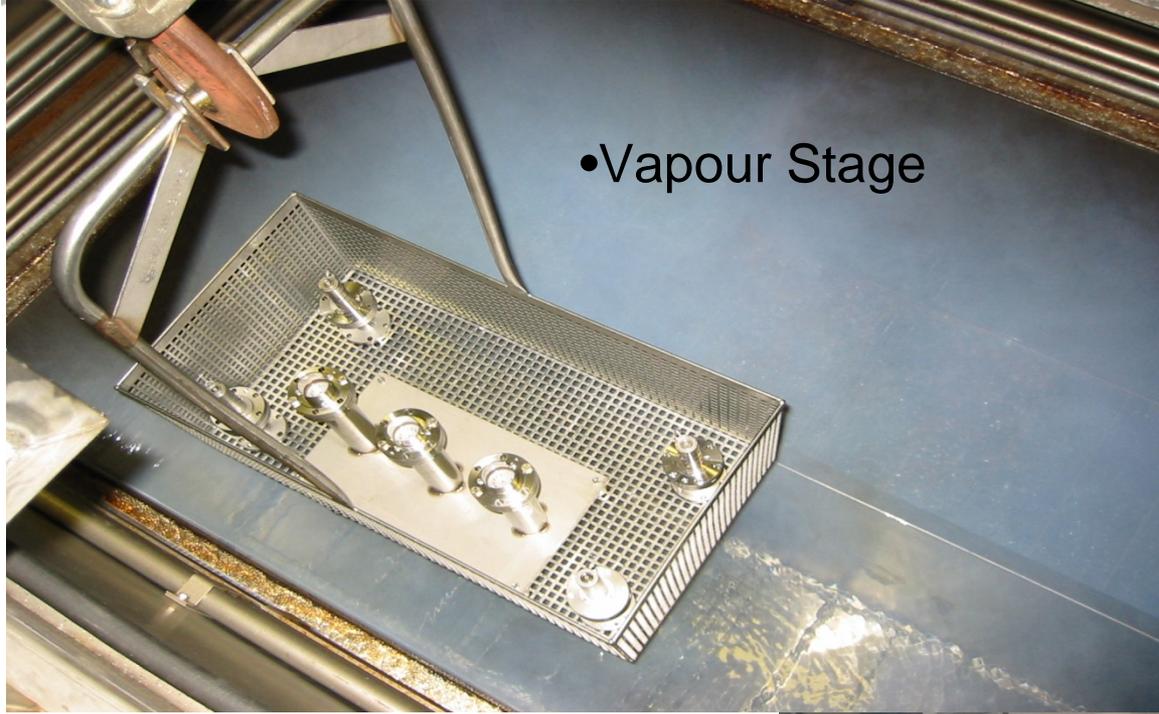
- Model E1500 – 1500mm x 500mm x 500mm
- Model S3000 – 3000mm x 600mm x 500mm



- 1 x Automatic solvent cleaning plant, model F100.

- 70% Trans-dichloroethylene,
- 10% Ethyl nonafluorobutyl ether,
- 10% Ethyl nonafluoroisobutyl ether,
- 5% Methyl nonafluorobutyl ether,
- 5% Methyl nonafluoroisobutyl ether.

Solvent Cleaning



•Vapour Stage



•Alkaline degreaser



- Hot drying cabinet.

Daresbury Cleaning History

Originally

- **CERN UHV Procedures Sufficient** (Ultrasonic and Vapour Cleaning)
 - Trichloroethane
 - CFC113 (Freon)
- **Alkaline Degreasing** (Almeco/CERN)
- **Glow Discharge** (added following research at Liverpool University)

1990's

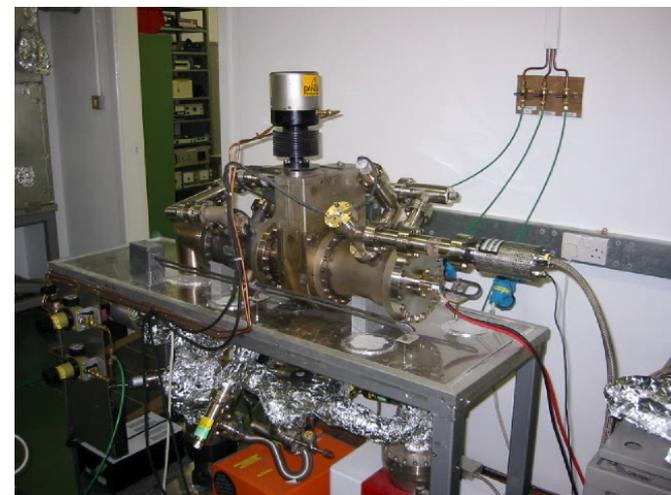
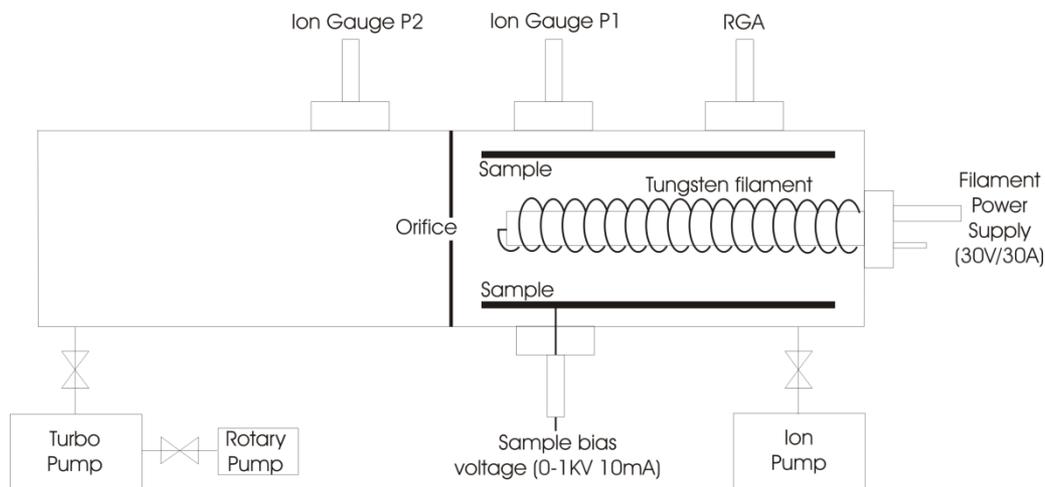
- **Research Study to find alternative solution due to Environmental Protection Legislation (e.g. Kyoto Protocol)**
 - Restricted use of Ozone depleting chemicals
 - Restriction then Ban of Trichloroethane and CFC113

Research Summary

- ✓ **Trichloroethylene** selected (comparable to Trichloroethane)
- ✗ **Aqueous** cleaners NOT SUFFICIENT alone but OK in combination with solvent.
- ✓ **Glow Discharge** – Dropped

Replacement of Trichloroethylene

- **What is important to us?** - Thermal outgassing and Stimulated Desorption



$$Q = \frac{P1 - P2}{A} \cdot C$$

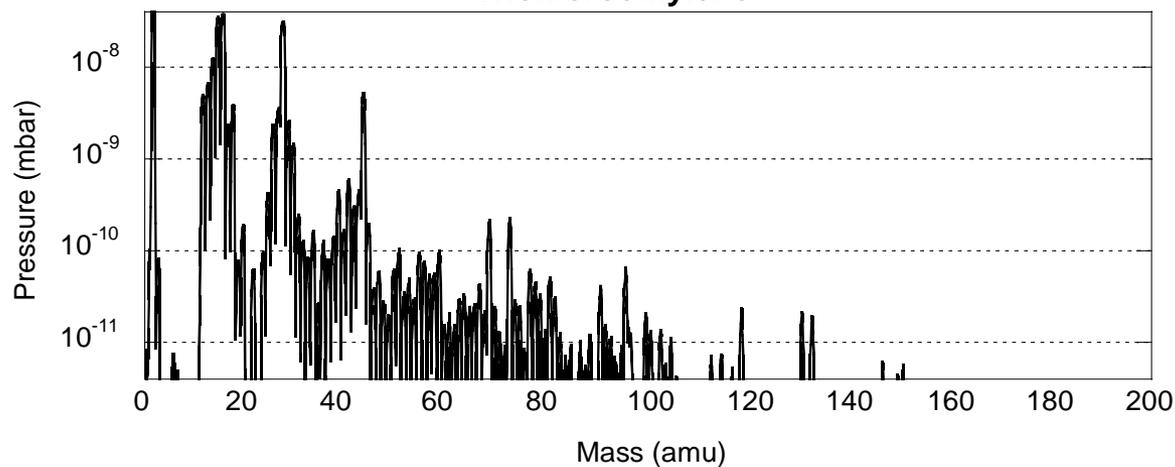
- **Comparative Tests** - existing procedure proven for 20 years

Cleaning Project Results

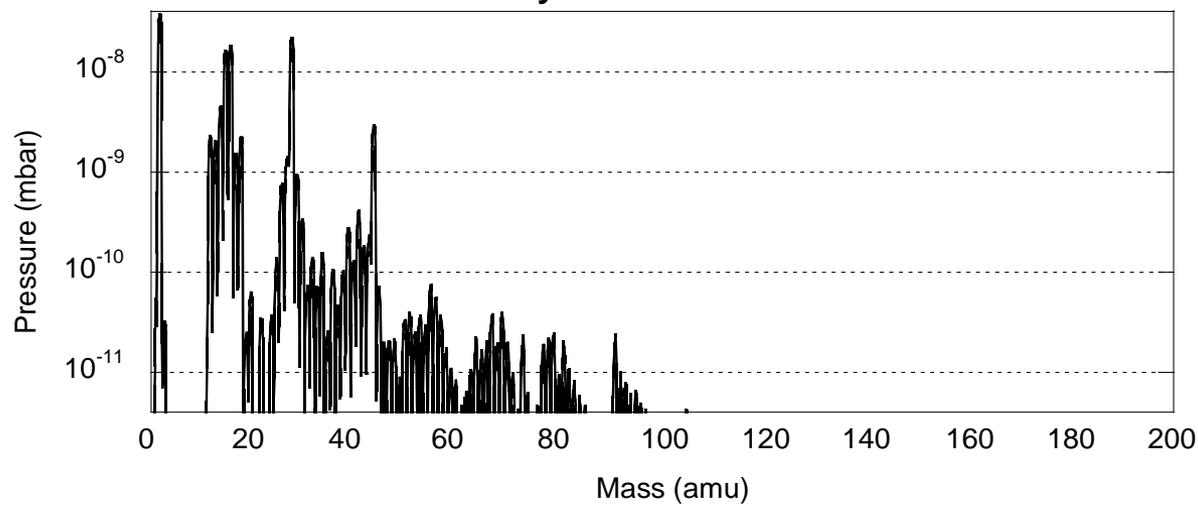
Cleaning Agent	Net thermal outgassing rate due to residual contaminants (mbar l s ⁻¹ cm ⁻²)	Hydrocarbon contamination (%)	Ratio of Mass 69 to Mass 28	Pressure rise from ESD (mbar)	Desorption Yield (molecules/electron)
Blank Run (No sample)	$8.2 \times 10^{-13} \pm 5.8 \times 10^{-13}$	0.46	1.8×10^{-4}	-	-
Trichloroethylene (No contamination)	$<2 \times 10^{-12}$	0.58	3.2×10^{-4}	-	-
Trichloroethylene (No contamination)	$<2 \times 10^{-12}$	0.53	8.3×10^{-4}	-	-
Trichloroethylene (Full contamination)	$<2 \times 10^{-12}$	0.90	8.5×10^{-4}	6.3×10^{-6}	0.055
Trichloroethylene (Full contamination)	$<2 \times 10^{-12}$	0.92	5.8×10^{-4}	-	-
n-propyl bromide 1 – Manufacturer 1	$<2 \times 10^{-12}$	1.34	6.1×10^{-4}	3.6×10^{-6}	0.29
n-propyl bromide 2 – Manufacturer 2	$6 \times 10^{-12} \pm 2 \times 10^{-12}$	2.52	1.9×10^{-2}	2.7×10^{-5}	2.19
Hydrofluoroether – Experiment 1	$<2 \times 10^{-12}$	0.52	4.3×10^{-4}	2.1×10^{-7}	0.017
Hydrofluoroether – Experiment 2	$<2 \times 10^{-12}$	0.86	2.7×10^{-4}	-	-
Isopropyl alcohol	$<2 \times 10^{-12}$	0.93	1.0×10^{-3}	4.3×10^{-6}	0.35
Aqueous cleaner 1	$<2 \times 10^{-12}$	2.86	1.6×10^{-3}	5.5×10^{-5}	4.46
Aqueous cleaner 2	$1.2 \times 10^{-11} \pm 2 \times 10^{-12}$	2.03	1.93×10^{-3}	3.7×10^{-5}	2.99
Aqueous cleaner 3	$<2 \times 10^{-12}$	2.70	2.2×10^{-3}	2.6×10^{-5}	2.12

ESD RGA data for HFE and Trike

Trichloroethylene



Hydrofluoroether



Cleaning Process Scientifically Developed

•Publications:

1. K.J. Middleman, J.D. Herbert, R.J. Reid, Vacuum 81 (2007) p793-798
2. J.D. Herbert and R.J. Reid, Vacuum, Vol. 47, 6-8, p693 (1996)
3. J.D. Herbert, R.J. Reid, A.E. Groome, J. Vac. Sci. Technol. A12(4), p1767, (1994)

- Considered aqueous and solvent based cleaning solutions
- Considered main gas loads in an accelerator – Thermal outgassing and stimulated desorption

•Conclusions

- Aqueous cleaners suitable only for thermal outgassing and not stimulated desorption
- Solvent based cleaners produced better results
- HFE (Hydrofluoroether) based solvent performed best, even better than our previous solvents

Dry Ice Cleaning

- Dry-ice or involves propelling pellets at extremely high speeds
- The pellets sublimate on impact with little energy transferred to the surface minimising any abrasion.
- The sublimation absorbs heat from the surface due to thermal shock. This removes the top layer of dirt/contamination.
- The rapid change in state from solid to gas causes microscopic shock waves which aid the removal of contamination.

- Main Uses:

- Food industry
- Semiconductor
- Aerospace
- RF structures for accelerators





Thermal Treatments

Thermal Treatment

Vacuum **Bakeout**

Vacuum Fire
(typical ~950C for
STST)

Air Bake
(up to ~ 400C)



Vacuum Firing

- The manufacturing process for steel means large quantities of H_2 are left in the bulk of the material.
- This H_2 is the limiting factor in achieving the best possible outgassing rates for UHV/XHV systems
- Vacuum firing (or annealing) involves heating the material to a high temperature ($\sim 950^\circ C$)
- This high temperature allows H_2 to diffuse from the bulk to the surface layers and allow it to be removed
- This process can improve the outgassing rate of steel by up to 2-3 orders of magnitude.
- The high temperature treatment is dependent on the permeability of a material, something which is very material specific



• Main Uses:

- Used in many industrial sectors as a way of performing processes in a controlled atmosphere (vacuum), the same process in air would lead to oxidation and the addition of contaminants

Bakeout

- Bakeout to moderate temperatures (250°C) is an efficient way of reducing outgassing, especially of water.
- In an accelerator, bakeout has to be undertaken with care to ensure temperature gradients are minimised and damage does not occur.
- Vessel supports must be designed to accommodate the movements due to thermal expansion and contraction (and so that vessels get back to where they started!)
- Bellows are used to accommodate these movements.



- With stainless steel, in machines the most common way to bake is to use wrapped heater tapes and bands with ceramic blanket insulation.
- For simpler vessels, close wrapped Kapton insulated printed heaters with superinsulation can be used to reduce the overall thickness to less than 1mm.
- For aluminium where temperatures used are less than 180°C, superheated water or wrapped film are used.



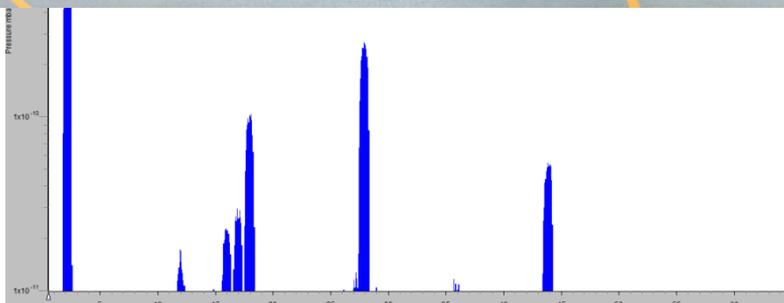
- Bakeout is best performed into external pumps, e.g. turbo pump sets.
- Towards the end, during cooldown, hot filament gauges should be degassed, *in situ* TSPs and NEG pumps carefully degassed and conditioned and ion pumps “flashed” for conditioning.
- Bakeout should be *monitored* rather than for fixed times – terminating when water in the rga spectrum falls to a predefined level.
- Heating and cooldown rates must be carefully controlled.

Bakeout In-Situ

- In situ bake laboratory established system.



HV in a
well
vacuum



Bakeout Ex-Situ

What is an acceptable RGA Scan?

- The residual gas spectrum MUST have been recorded over 1 – 200 amu
- The limits shown in Table 1 below are expressed in terms of percentages of the total pressure in the system.
- The definition of “general contaminants” is the sum of the partial pressures of all peaks present in the residual gas spectrum of mass to charge ratio (amu) equal to 39, 41-43 and 45 and above (excluding any above 45 specifically listed in the table below). Also to be excluded from this summation are any peaks related to the rare gases xenon (i.e. 132, 129, 131) and krypton (i.e. 84, 86, 83)
- The level of “general contaminants” in the system shall be calculated. It shall sum all general contaminant peaks as defined in point 3 above and divide this number by the total pressure (excluding peaks at any water peaks at Masses 17 & 18 amu) then multiply by 100 to give the answer as a percentage.
- The total pressure **MUST** be $< 10^{-7}$ mbar or below before the calculation is performed.
- There are 2 acceptance criteria as shown in table 1 below:
 - Line 1 assumes the component to be tested has been baked ‘in-situ’ and therefore the vacuum pressure should be below 10^{-9} mbar.
 - Line 2 assumes the component to be tested has **NOT** been baked ‘in-situ’ and therefore the pressure achieved will not reach 10^{-9} mbar, however, it must be $< 10^{-7}$ mbar.

Table 1: Acceptable levels of general contaminants for the ESS BTM Project

Line Number	Pressure Region	General Contaminants (%)	Perfluoropolyphenylethers Sum of (peak at 69 and 77 amu) (%)	Chorinated species (Sum of peaks at 35 and 37 amu) (%)	Comment
1	UHV	0.1	0.01	0.01	Assuming system baked. Calculation to be done at 10^{-9} mbar or below
2	HV - UHV	0.75	0.075	0.075	Assuming system unbaked. Calculation to be done at 10^{-7} mbar or below

Bakeout Ex-Situ

- Following ex situ bakeout and when acceptable standards have been achieved it is critical that the vessel be handled and treated the right way.
- How?
 - Ensure system is vented with a 'dry' inert gas to prevent any re-adsorption, typically N₂ or Ar are used.
 - Define what is 'dry'?
 - For accelerators we want to minimise the re-adsorption of water, therefore before venting we measure the dew point of the inert gas down to -70°C.
 - Store the vessel appropriately, sealed off until ready for use.
 - We have experience to show that vessels that have been handled and stored correctly remain suitable for use months later.
 - When ready to use or install the vacuum chamber ensure any exposure to air is minimised to the shortest time practically possible. Also use a 'dry' N₂ purge to ensure no water ingress from the surrounding air.

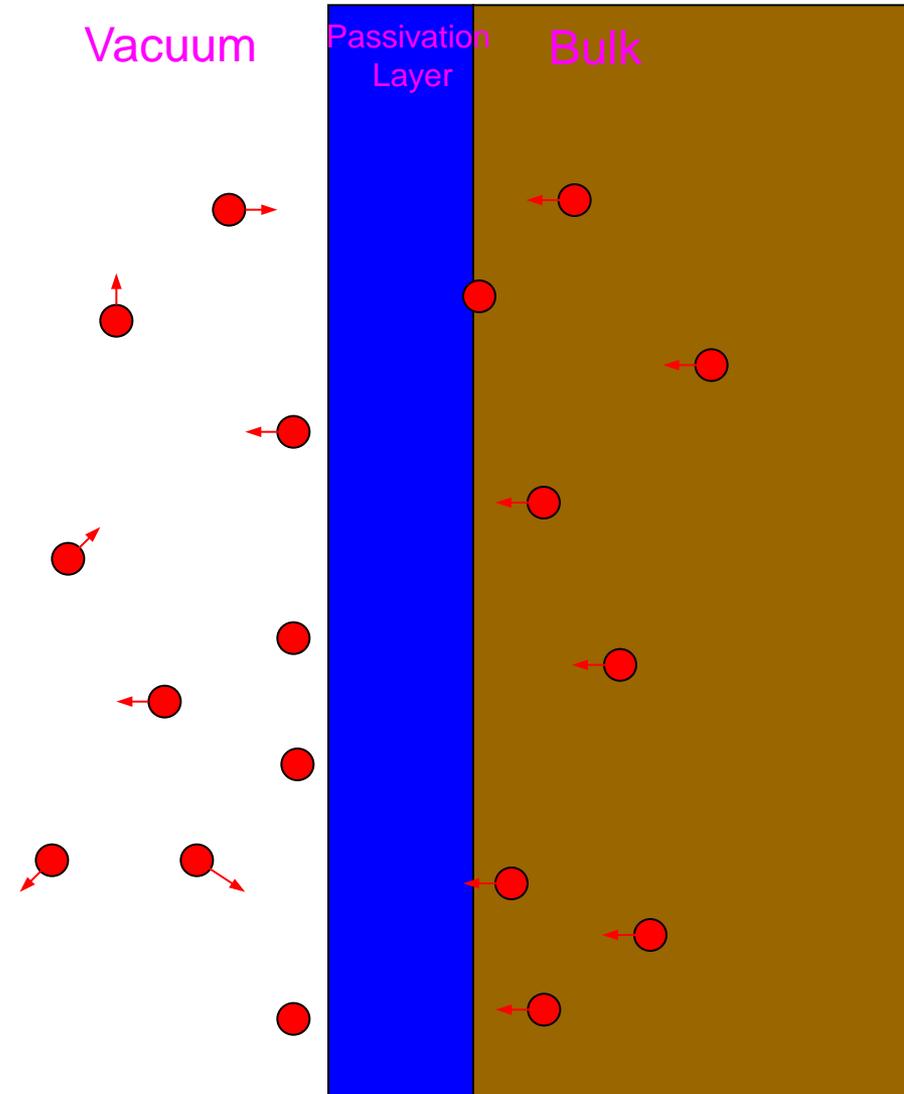


Passivation Techniques

- Using barriers to inhibit outgassing
 - Air Baking
 - Electropolishing
 - NEG or TiN coatings
- But note that **all** of these have some cleaning effect!

What is Passivation?

- The use of a barriers to inhibit outgassing
 - Coatings
 - NEG
 - TiN
 - Surface modifications
 - Electropolishing
 - Acid Etching
 - Laser modified surfaces





Air Baking

- The simple process of heating a vacuum chamber to a particular temperature in air.
- Typically baked to around 400°C
 - Helps remove H₂ from the bulk but at a lower temperature the rate of diffusion is much lower, therefore not as effective at depleting H₂ reservoirs as vacuum firing
 - Cheaper than vacuum firing
 - Visually the vacuum components have a dull colour
- Forms an oxide layer on the vacuum chamber, this helps minimise the desorption of contaminants from the vacuum surface into the vacuum.

M. Bernardini et al [7] Hydrogen is most responsible gas of outgassing rates also in SS vacuum chamber. Heating the raw material at 400 °C in air was suggested as a money saving alternative to the classical vacuum heating at 950 °C. In this paper concluded that air bake-out drives out most of the hydrogen absorbed in the bulk stainless steel. Results show that bake-out in air is effective in reducing the hydrogen outgassing rate of a very large stainless steel vacuum chamber. The hydrogen content and the diffusion parameters for a 304 L type stainless steel have been measured by desorption tests on small samples. It is concluded that the effect of the heating treatment in air is mainly to reduce the hydrogen content. Outgassing rate can be decreased with baking of materials as shown in figure 4.

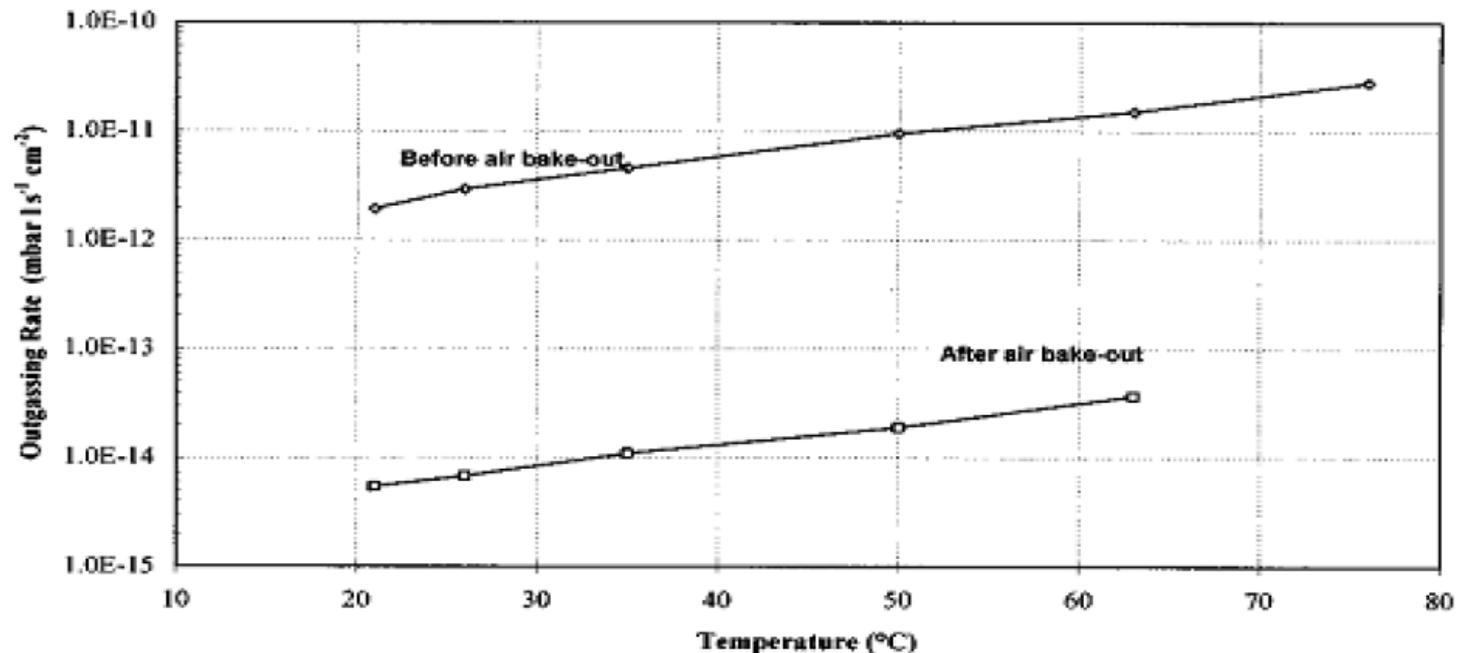


Figure 4. Hydrogen outgassing rate with and without air baking [7]

[7] M. Bernardini, S. Braccini, R. De Salvo, G. Genuini, Z. Zhang, "Air bake-out to reduce hydrogen outgassing from stainless steel," *Journal of Vacuum and Science Technology*, vol. 1, no. 16, pp. 188-193, 1998.

What NEG coating does

1) Reduces gas desorption:

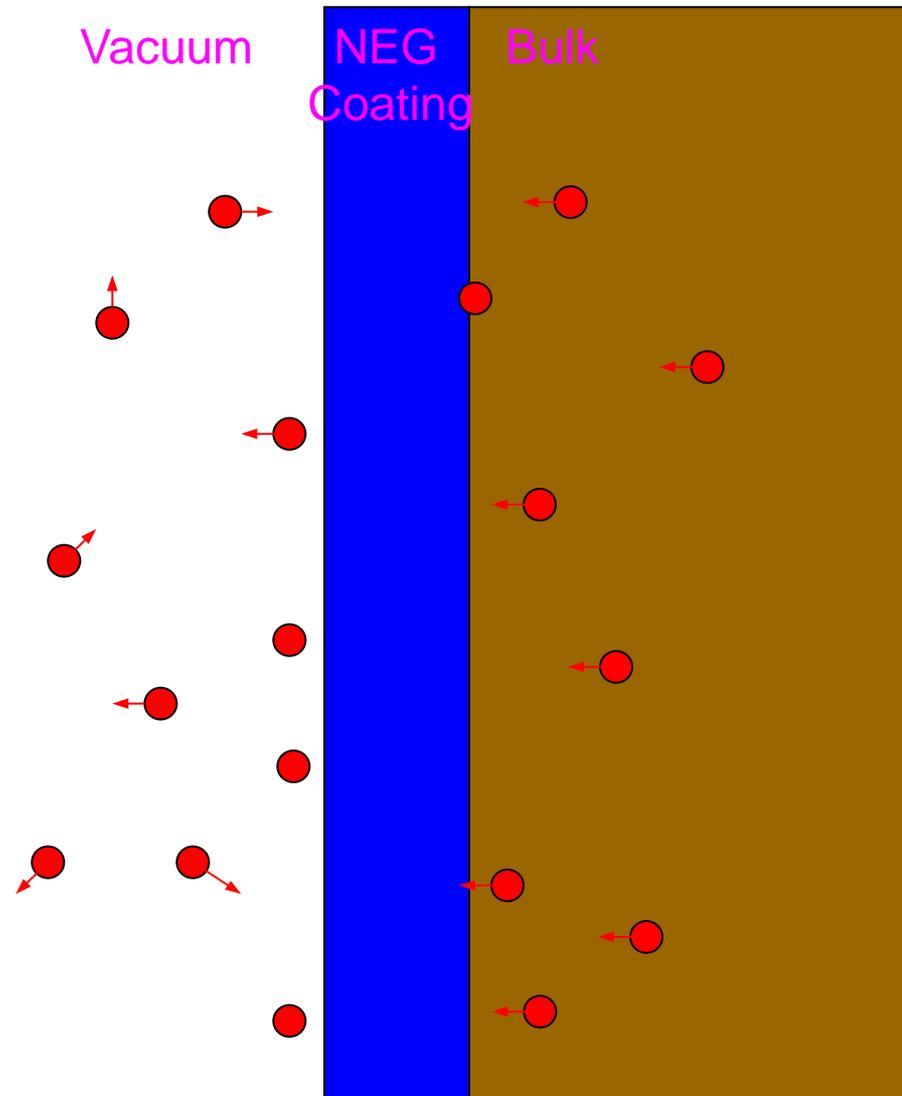
- A pure metal (Ti, Zr, V, Hf, etc.) film ~1- μm thick without contaminants.
- A barrier for molecules from the bulk of vacuum chamber.

2) Increases distributed pumping speed, S :

- A sorbing surface on whole vacuum chamber surface

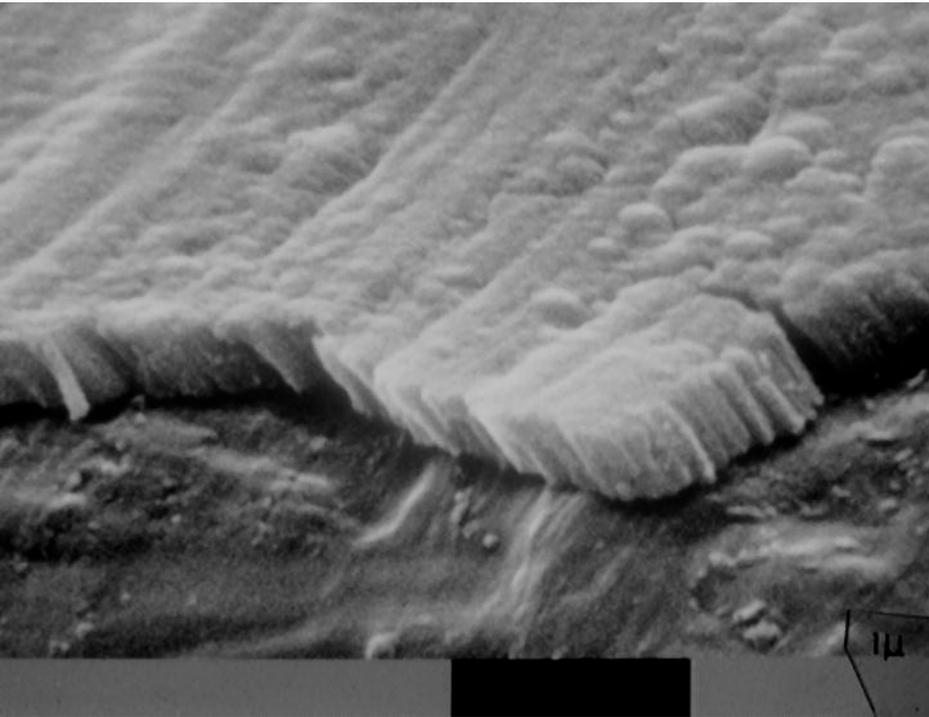
$$S = \alpha \cdot A \cdot v / 4;$$

where α – sticking probability,
 A – surface area,
 v – mean molecular velocity

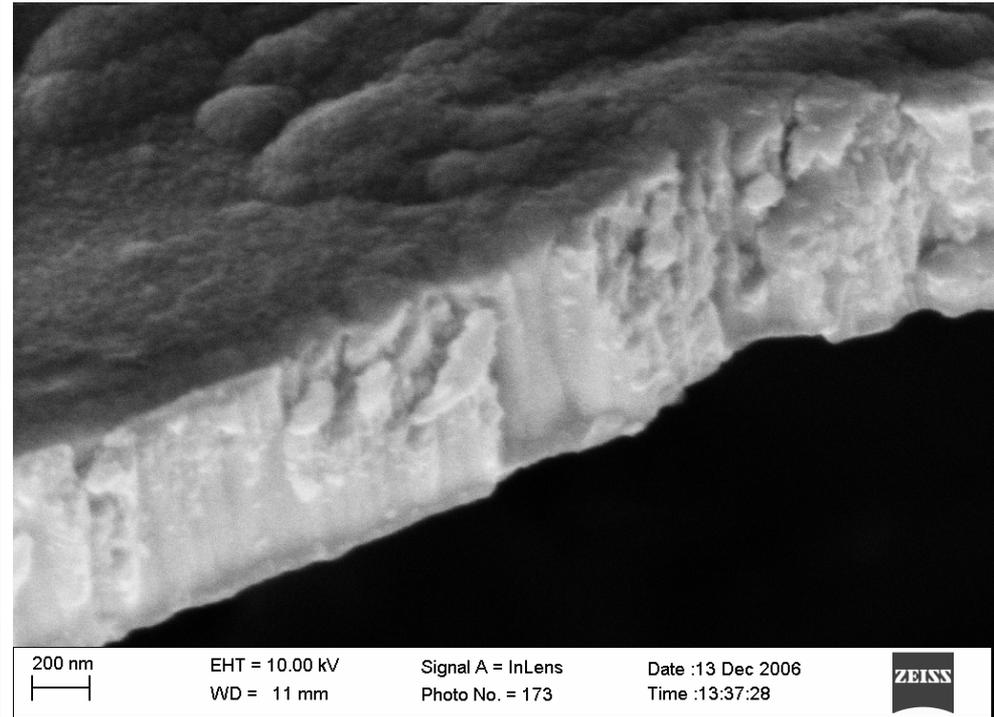


SEM images of films (film morphology)

- columnar



dense



•O.B. Malyshev, R. Valizadeh, J.S. Colligon *et al.* J. Vac. Sci. Technol. A 27 (2009), p. 521.

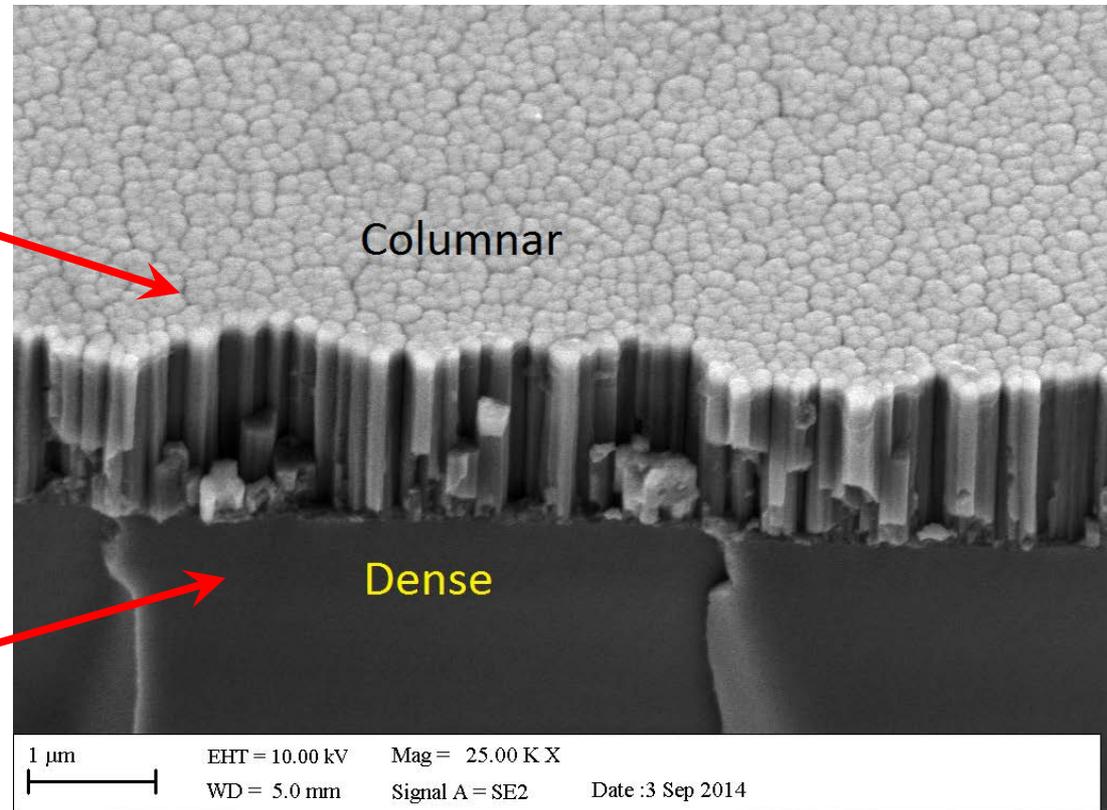
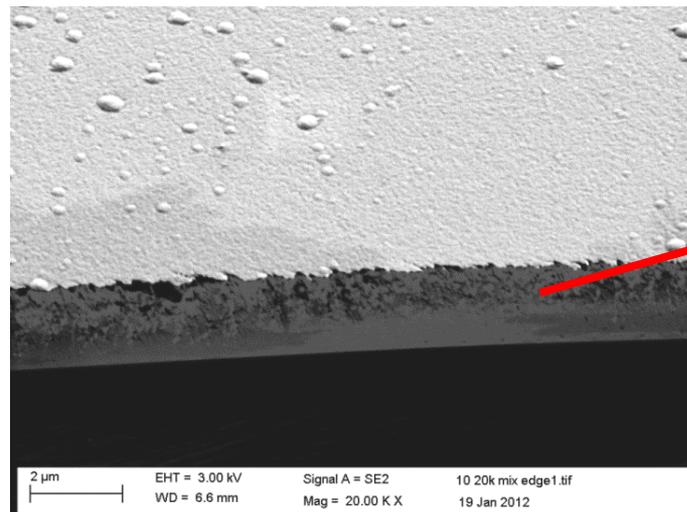
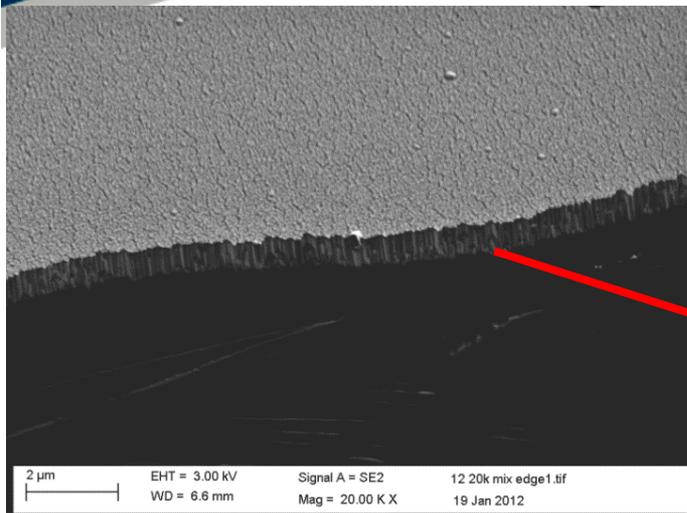
Vacuum

- Columnar layer:
 - Activated at lower temperature
 - Provides higher sticking probability and pumping capacity
- Dense layer:
 - Provides lower ESD
- Dual Layer:
 - Combines benefit of both
 - For more details: see A. Hannah's poster EM286 on Thursday

Columnar NEG Coating

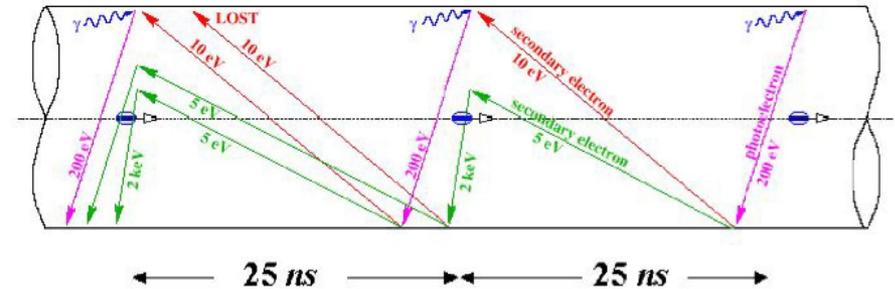
Dense NEG Coating

Bulk metal



Why are high SEY materials a problem?

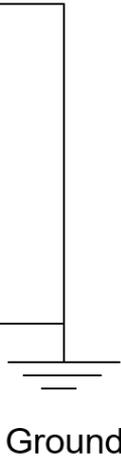
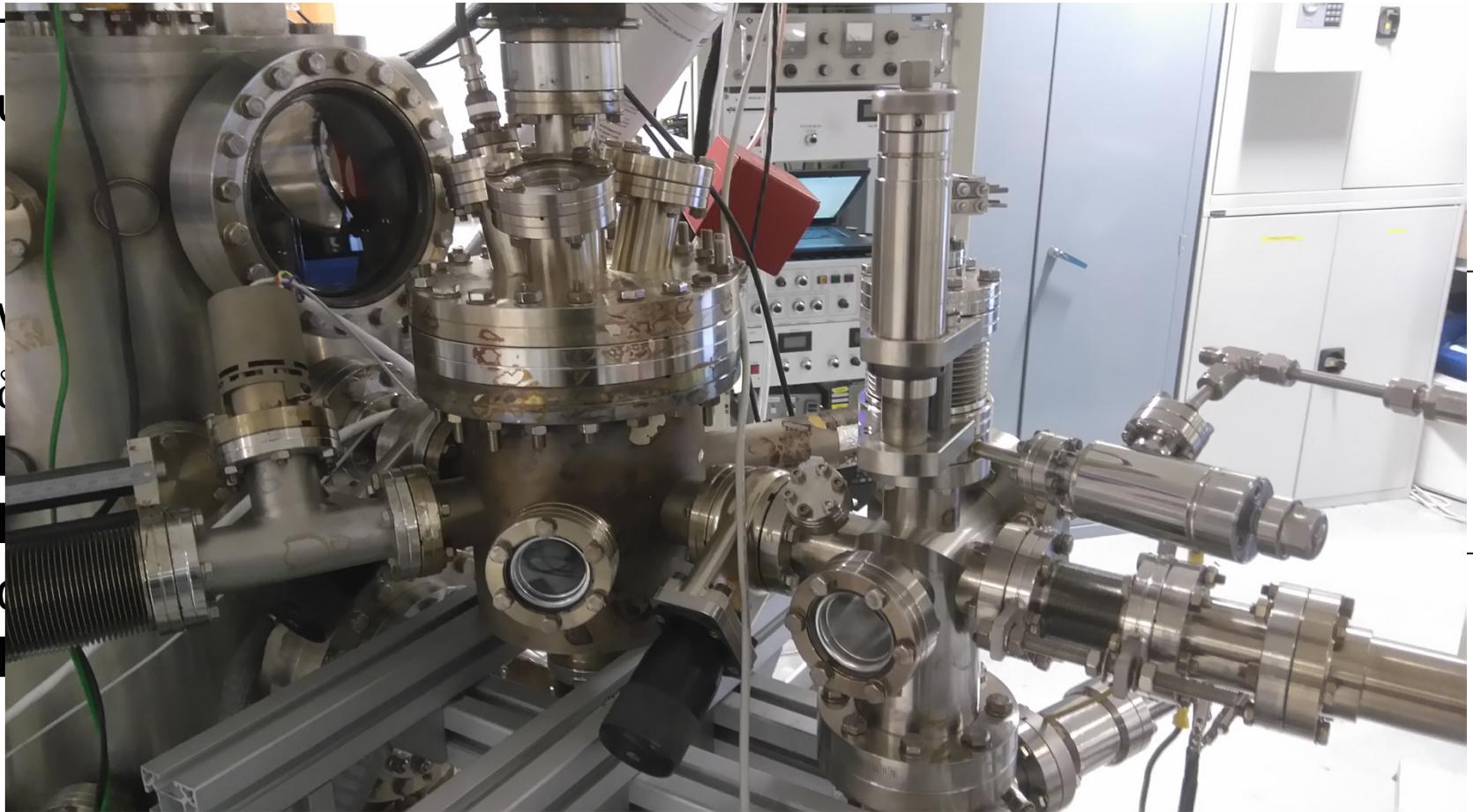
- High SEY materials are a problem in positively charged accelerators
- When a charged particle is accelerated it emits Photons
- These photons release electrons in the wall via the photoelectric effect and also ionise residual gas in the chamber
- For future accelerators the optimum situation is to have a $SEY < 1$



• Illustration of electron cloud build up by F.Ruggiero

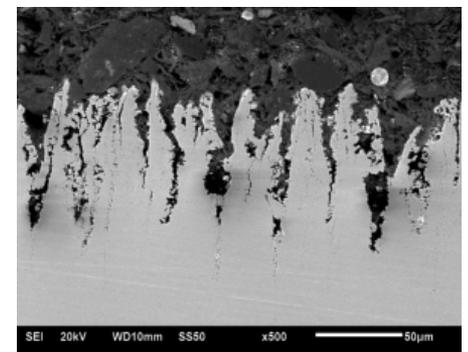
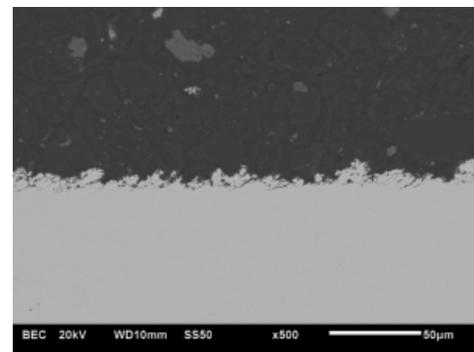
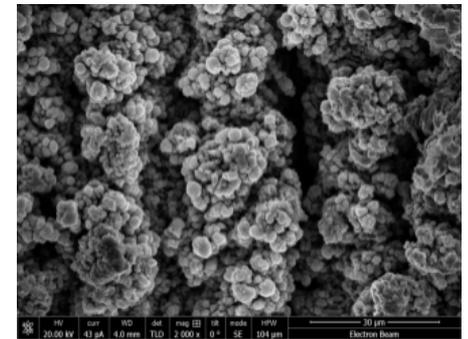
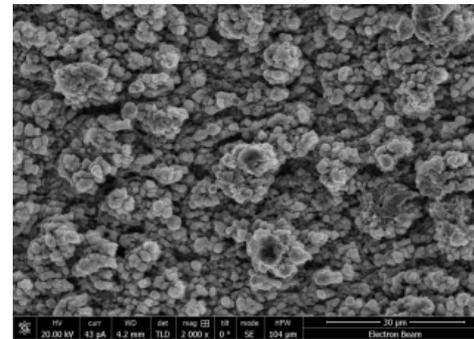
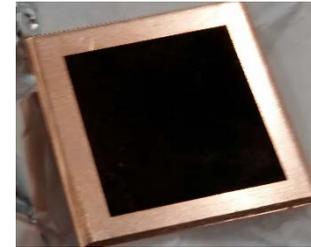
- The next bunch of photons accelerate the electrons into the opposite wall creating more electrons
- Causes the build up of an electron cloud

SEY measurement facility



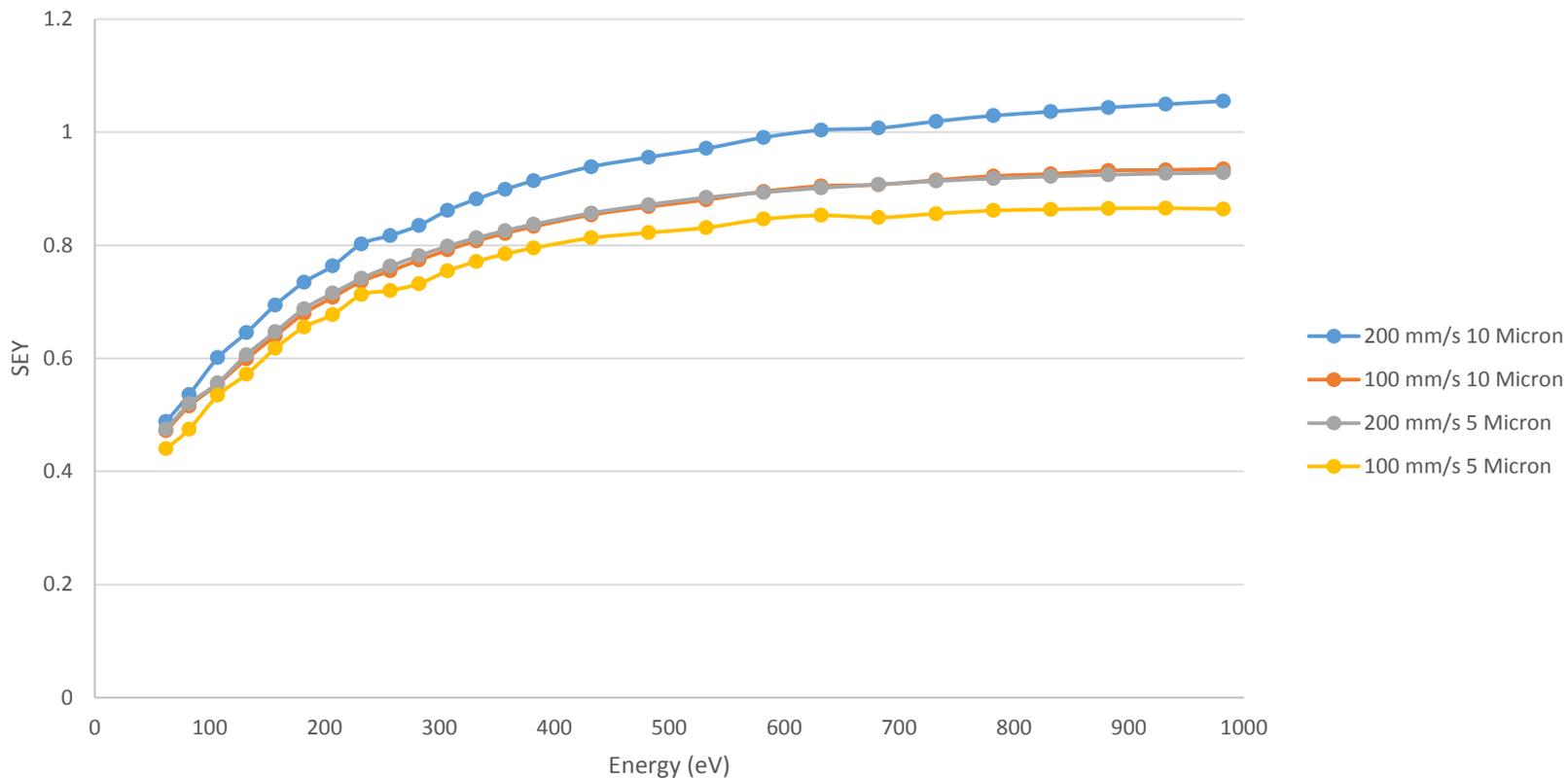
Laser Treated Copper

- Surfaces have a micro and nanostructure
- Optically black
- Various laser parameters can be varied to change the topology
- Such modified surfaces increase surface area and therefore outgassing is likely to be higher
- Surface resistance is also increased – a potential issue for accelerators



SEY measurements

Micronanics Samples

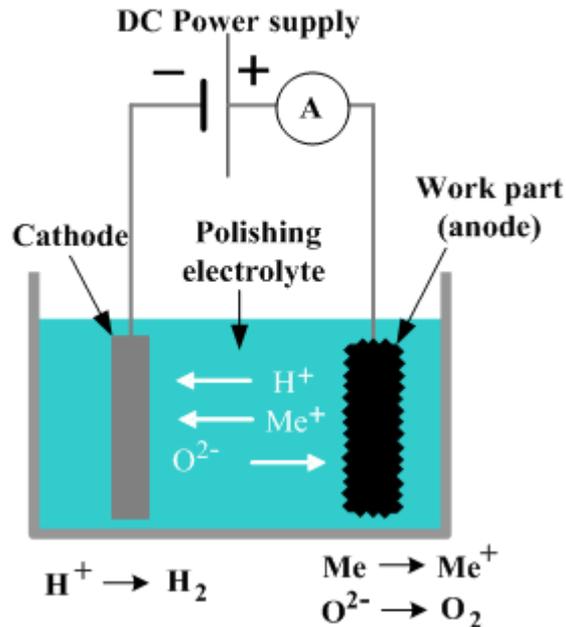


- For use in vacuum polishing techniques are often employed.
- Polishing effectively reduces the surface area, if we reduce the surface area then we potentially reduce the outgassing rate.
- This may NOT always be the case, polishing can actually grind contaminants into the surface or leave particular species in the subsurface layers – mainly H_2
- For polishing techniques to be completely effective they are often finished with some additional technique – mainly heating
- Electropolishing followed by vacuum firing can produce outgassing rates in 10^{-14} mbar l/s/cm² range and give a nice surface finish but the electropolishing doesn't improve significantly the outgassing rate compared to just vacuum firing.
- Polishing techniques are often used for additional purposes and not necessarily for vacuum performance

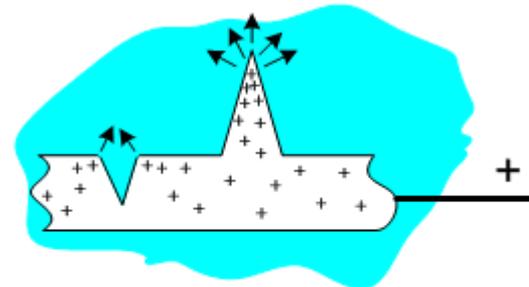
- In order to remove any defects or damage to the surface, an acid etch is applied to the cavities
 - ⇒ Buffer Chemical Polish (BCP) removes 100-150 μm
- Acid mixture
 - Hydrofluoric acid; HF (49%)
 - Nitric Acid; HNO₃ (65%)
 - Phosphoric Acid; H₃PO₄ (85%)
 - In a 1:1:1 mixture
- Risk of hydrogen contamination
 - Correct mixture should be used
 - Temperature of acid should be kept below <18 °C, to control the exothermic reaction
 - Vacuum processing required
- Cavity is the high pressure rinsed (HPR) with ultrapure water



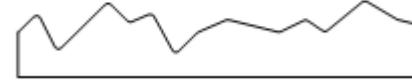
Electropolishing



Electrical potential distribution



Surface profile before electropolishing

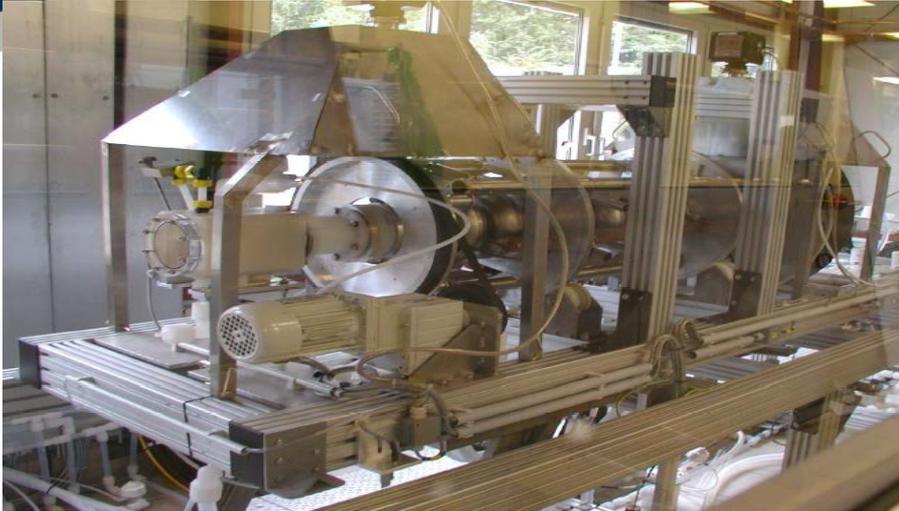


Surface profile after electropolishing

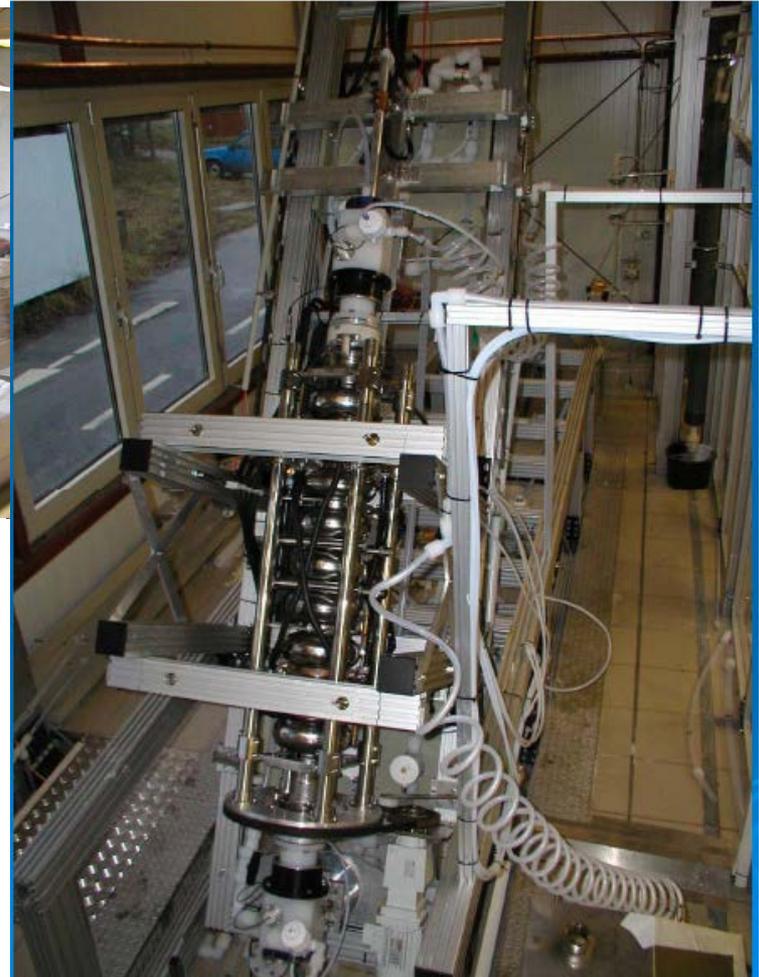


- Work piece acts as the anode
- A current passes from the anode & the surface is oxidised and dissolved into the electrolyte.
- At the cathode Hydrogen is produced as a by product

Electropolish (EP)



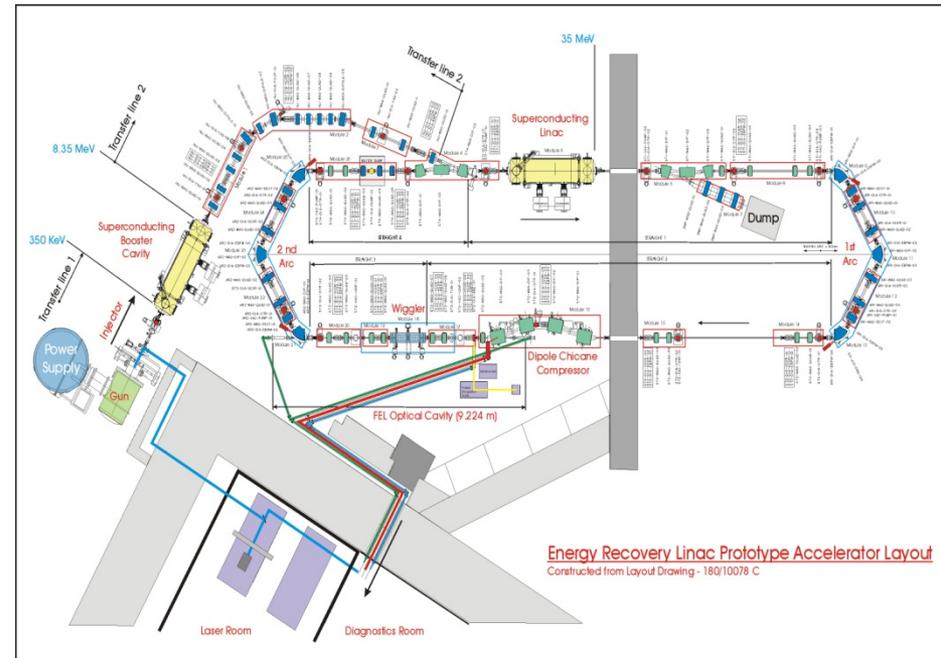
- Electropolishing achieves a smoother finish than BCP and typically higher gradients
- The cavity is an anode and an aluminium cathode is immersed in an electrolyte
- Again hydrogen is produced so vacuum processing and HPR are required



Current and Future Challenges

- Currently Developing XHV and Low Particle Processing Techniques

- Use of SRF ($P_T < 10^{-10}$ mbar, low levels of particles and surface contaminants)
- Requirements for High Average Current Photoinjectors ($P_T < 10^{-11}$ mbar, $P_{O_2} < 10^{-14}$ mbar, low levels of particles and surface contaminants)
- Reduce gas density in region of photo-injector
- E.g. To reduce **ion back bombardment** on photocathode material and to prevent **cathode poisoning**. May lead to reduced QE.

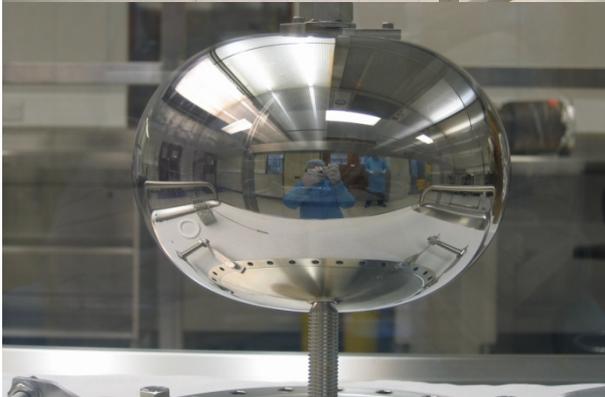
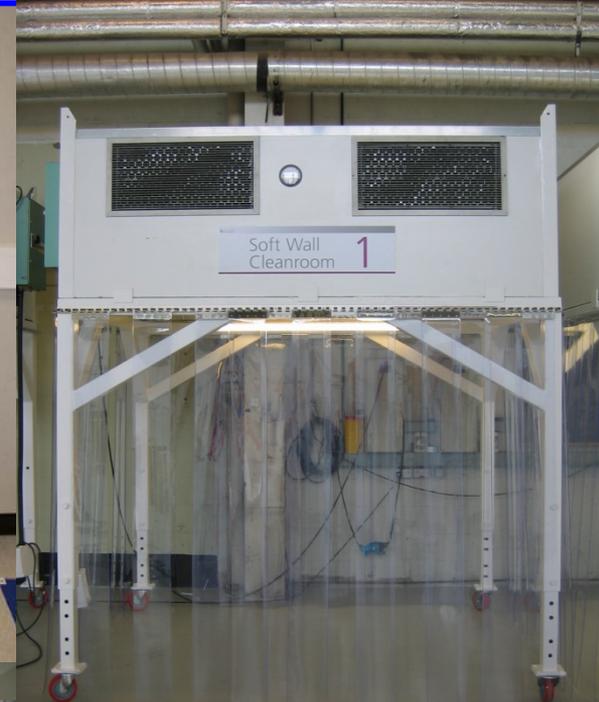




Dust particles in a vacuum chamber

- The dust *micro-particle* in the beam vacuum chamber might be ionised by photons or photoelectrons and then be *trapped by the beam* electric field.
- This may cause *the significant loss of the beam*.
- Potential sources of the dust micro-particles :
 - Dust from the atmosphere during storage, installation or venting
 - Dust from moving parts: manipulators, bellows, valves, etc
 - Micro-particles from getters, cryosorbers
 - Micro-particles from working IP.
- How to avoid:
 - Proper cleaning and storing
 - Positioning of potential dust sources in regard to the beam
 - Clean environment when vacuum chamber is open
 - Clean gas for venting (for example, boil-off nitrogen)

Particle Control



CLEANROOM TECHNOLOGY

THE BASIS OF CLEANROOM STANDARDS

The unit of measurement is a micrometric one micrometer (1µm being one millionth of a metre). The drawings below compare particle sizes.

1) Human hair which can readily be appreciated is approximately 70 - 100 µm in diameter.	2) The size of a particle that can be seen on a surface is approximately 10µm in diameter.	3) The particle size which the clean area is limited at is 0.5 µm.
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People can tolerate millions of particles and thousands of microns carrying particles from their skin and clothing. It is therefore necessary for personal working within the clean area to change into the correct cleanroom clothing to minimise the dispersion.

WHAT IS A CLEANROOM

It is a room in which the concentration of airborne particles are controlled, and which is controlled and used in a manner to minimise the introduction, generation and retention of particles inside the room.

PERSONAL ITEMS	PERSONAL BEHAVIOUR
<p><i>These articles are not allowed into the Clean Area.</i></p> <ul style="list-style-type: none"> • Food, drink and sweets • Smoking material • Watches, Cell Phones, Pagers, etc. • Newspaper, magazines, books, etc. • Breath analyser, etc. • Watches, pens, calculators and rings 	<p><i>The following suggestions of indoor concentration within the Clean Room Area:</i></p> <ul style="list-style-type: none"> • No talking, coughing or sneezing directly over the product • Do not touch surfaces or products with skin • Minimal movement is allowed • Masks must not be worn below the nose • Change Area floor must be swept before opening 'clean Area door'

ENTRY AND EXIT OF PERSONNEL	
<p style="text-align: center;">ISO 7</p> <p>ENTRY ISO 7 / ISO 8 CLASS</p> <ol style="list-style-type: none"> 1. Disposable footwear coverings or dedicated shoes 2. Changing gloves 3. Disposable bouffant hat or hairnet 4. Coat 5. Sit on the stooper and using legs over whilst putting on a extra pair of foot covering 6. Remove donning gloves and use latex gloves. <p>EXIT ISO 7 / ISO 8 CLASS</p> <ol style="list-style-type: none"> 1. Remove gloves and place on hangers 2. Dispose of bouffant, shoes and gloves. 	<p style="text-align: center;">ISO 4</p> <p>ENTRY ISO 4 / ISO CLASS</p> <ol style="list-style-type: none"> 1. Disposable footwear coverings or dedicated shoes 2. Donning gloves 3. Disposable bouffant hat or hairnet 4. Coat and suit 5. Cover all (without touching the floor) 6. Sit on stooper and using legs over whilst putting on over boots 7. Remove donning gloves and use ISO 5 latex gloves to enter booth. <p>EXIT ISO 4 / ISO CLASS</p> <ol style="list-style-type: none"> 1. Remove outer boots, coverall and hood. Place in plastic container and return for 2. Use use only. 2. Dispose of bouffant, shoes, mask and gloves.





Particle Control

- Systems of flushing and counting particles
- Use of Clean Hoods and Clean Rooms
- Careful Design to Minimize Particle Sources or Position Them Safely away from Beam.
- Careful Selection of in-vacuum components
- Use of gas filters during let up
- Controlled gas flow (pump down/letup speed)
- **Good Cleaning Procedures**



Summary

- General factors affecting Vacuum
- Considerations for cleaning – why we need it, define your specification
- Cannot increase pumping speed massively but can reduce outgassing rates considerably
- Demonstrated why cleaning is so important for UHV/XHV in reducing outgassing rates
- Discussed the importance of quality control
- Reviewed various processes which are known to affect vacuum performance
- Introduced particle control procedures